



Contribution ID: 457

Type: Poster

## Design of a dual-band IR imaging system for surface temperature measurements on the tungsten divertor in EAST

Wednesday 7 June 2017 13:40 (2 hours)

In 2018, EAST will be operated with a full tungsten (W) divertor in both the upper and lower divertors. Tungsten is a shiny refractory metal; as such, its emissivity in the infrared (IR) range is low. In addition film formation on the tungsten alters the emissivity, which makes precise surface temperature measurements difficult for conventional single-band IR cameras. To resolve this problem, a dual-band IR imaging system has been planned to install into EAST, to more accurately measure the surface temperature on the W divertor. The dual-band IR system has the advantage of being mostly independent of surface emissivity; using pyrometric techniques, the surface temperature is calibrated by the ratio of signals in two bands [1]. A commercial single-band mid-wavelength IR camera combined with a two-band IR adapter is designed with a field of view  $5.5 \times 2.2$ . The two-band IR adapter utilizes a dichroic beam splitter, which reflects  $3.7\text{--}4.2\mu\text{m}$  wavelengths and transmits  $4.3\text{--}4.8\mu\text{m}$  wavelength radiation, each with  $>90\%$  efficiency and projects each IR channel image side-by-side on the camera's detector. The dual-band IR images system will be used to monitor the upper outer W divertor with an existing mirror, with a  $\sim 1\text{mm}$  spatial resolution. In addition, a mirror installed into Material and Plasma Evaluation System [2] is designed for the measurement of the surface temperature on the lower outer divertor.

[1] A.G. McLean et al., Rev. Sci. Instrum. 83, 053706 (2014)

[2] F. Ding et al., Journal of Nuclear Materials 455 (2014) 710–716

\*This work was supported by DoE Contracts: DE-AC05-00OR22725, and DE-AC02-09CH11466

### Eligible for student paper award?

No

**Authors:** GRAY, Travis (Oak Ridge National Laboratory); Dr MAINGI, Rajesh (Princeton University Plasma Physics Laboratory Princeton); WIRTH, Brian (university of Tennessee); GAN, kaifu (university of Tennessee, Knoxville)

**Presenter:** GAN, kaifu (university of Tennessee, Knoxville)

**Session Classification:** W.POS: Poster Session W

**Track Classification:** Diagnostics and instrumentation